

# Memory FeRAM

# 256K (32K × 8) Bit SPI

# MB85RS256TYA

#### **■ DESCRIPTION**

MB85RS256TYA is a FeRAM (Ferroelectric Random Access Memory) chip in a configuration of 32,768 words  $\times$  8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells. This product is specifically targeted for high-temperature environment such as automobile applications.

MB85RS256TYA adopts the Serial Peripheral Interface (SPI).

The MB85RS256TYA is able to retain data without using a back-up battery, as is needed for SRAM. The memory cells used in the MB85RS256TYA can be used for 10<sup>13</sup> read/write operations, which is a significant improvement over the number of read and write operations supported by Flash memory and E<sup>2</sup>PROM.

As MB85RS256TYA does not need any waiting time in writing process, the write cycle time of MB85RS256TYA is much shorter than that of Flash memories or E<sup>2</sup>PROM.

#### **■ FEATURES**

Bit configuration
 Special Sector Region
 32,768 words × 8 bits
 256 words × 8 bits

In this region, data storage after (by) three times reflow based on

JEDEC MSL-3 standard condition is guaranteed.

Unique ID

• Serial Number : 64 bits

In this region, data storage after (by) three times reflow based on

JEDEC MSL-3 standard condition is guaranteed.

• Serial Peripheral Interface : SPI (Serial Peripheral Interfaces)

Correspondent to SPI mode 0 (0, 0) and mode 3 (1, 1)

Operating frequency
 High endurance
 Data retention
 50 MHz (Max)
 10<sup>13</sup> times / byte
 70.4 years (+85 °C)
 19.1 years (+105 °C)

19.1 years (+105 C)

5.9 years (+125 °C) or more Under evaluation for more than 5.9 years(+125 °C)

• Operating power supply voltage : 1.8 V to 3.6 V

Low power consumption
 Operating power supply current 3.7mA (Max@50 MHz)

Standby current 150µA (Max)

Deep Power Down current 30μA (Max)

Hibernate current 10µA (Max)

- Operation ambient temperature range :  $-40\ ^{\circ}\text{C}$  to +125  $^{\circ}\text{C}$ 

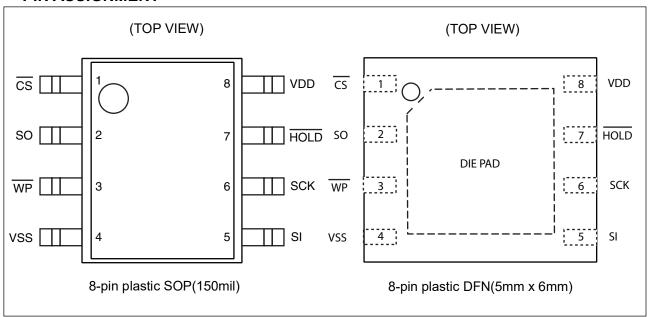
Package
 8-pin plastic SOP (150mil)

8-pin plastic DFN (5mm x 6mm)

RoHS compliant

Fujitsu Semiconductor Memory Solutions Limited has changed its name to RAMXEED Limited. RAMXEED Limited will continue to offer and support existing products while maintaining Fujitsu's part number unchanged.

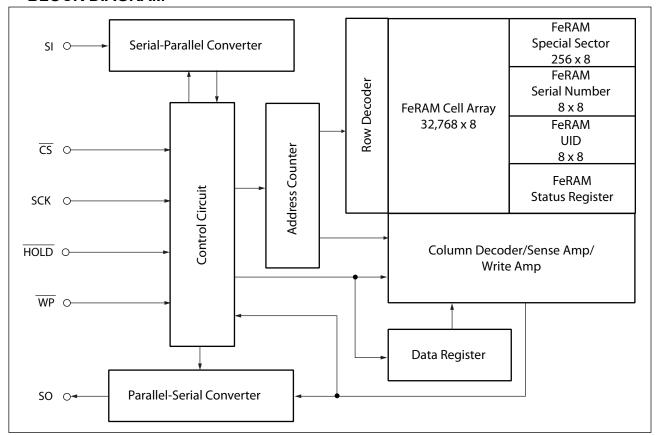
#### ■ PIN ASSIGNMENT



#### **■ PIN FUNCTIONAL DESCRIPTIONS**

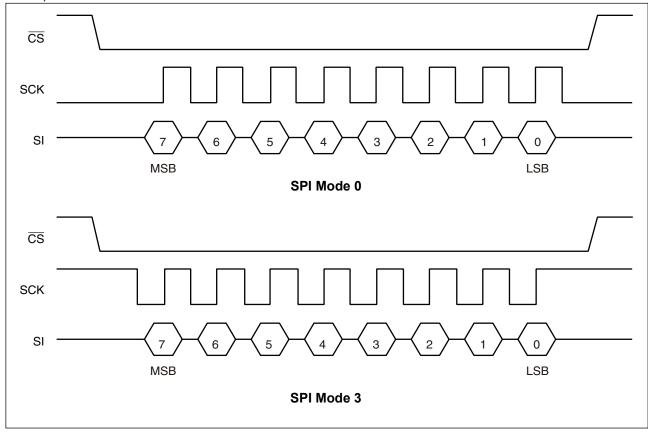
Pin No.	Pin Name	Functional description
1	CS	Chip Select pin This is an input pin to make chips select. When $\overline{CS}$ is "H" level, device is in deselect (standby) status and SO becomes High-Z. Inputs from other pins are ignored for this time. When $\overline{CS}$ is "L" level, device is in select (active) status. $\overline{CS}$ has to be "L" level before inputting op-code.
3	WP	Write Protect pin This is a pin to control writing to a status register. The writing of status register (see "■ STATUS REGISTER") is protected in related with WP and WPEN. See "■WRITING PROTECT" for detail.
7	HOLD	Hold pin  This pin is used to interrupt serial input/output without making chips deselect. When HOLD is "L" level, hold operation is activated, SO becomes High-Z, SCK and SI become do not care. See "■HOLD OPERATION" for detail. The Hold pin is pulled up internally to the VDD pin.
6	SCK	Serial Clock pin This is a clock input pin to input/output serial data. SI is loaded synchronously to a rising edge, SO is output synchronously to a falling edge.
5	SI	Serial Data Input pin This is an input pin of serial data. This inputs op-code, address, and writing data.
2	so	Serial Data Output pin This is an output pin of serial data. Reading data of FeRAM memory cell array and status register data are output. This is High-Z during standby.
8	VDD	Supply Voltage pin
4	VSS	Ground pin

#### **■ BLOCK DIAGRAM**



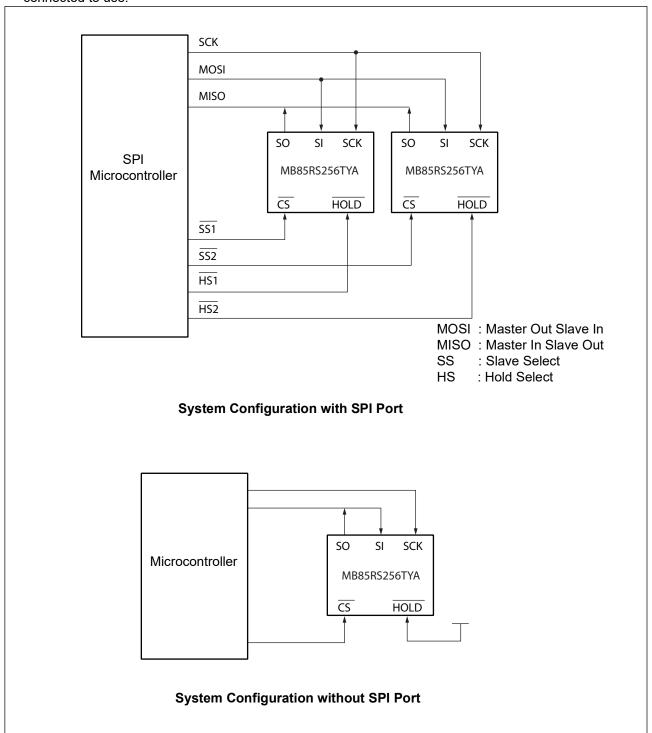
#### ■ SPI MODE

MB85RS256TYA corresponds to the SPI mode 0 (CPOL = 0, CPHA = 0), and SPI mode 3 (CPOL = 1, CPHA = 1).



### ■ SERIAL PERIPHERAL INTERFACE (SPI)

MB85RS256TYA works as a slave of SPI. More than 2 devices can be connected by using microcontroller equipped with SPI port. By using a microcontroller not equipped with SPI port, SI and SO can be bus connected to use.



#### **■ STATUS REGISTER**

Bit No.	Bit Name	Function
7	WPEN	Status Register Write Protect This is a bit composed of nonvolatile memories (FeRAM). WPEN protects writing to a status register (refer to "■ WRITING PROTECT") relating with WP input. Writing with the WRSR command and reading with the RDSR command are possible.
6 to 4	_	Not Used Bits These are bits composed of nonvolatile memories, writing with the WRSR command is possible. These bits are not used but they are read with the RDSR command.
3	BP1	Block Protect This is a bit composed of nonvolatile memory. This defines size of write
2	BP0	protect block for the WRITE command (refer to "■ BLOCK PROTECT"). Writing with the WRSR command and reading with the RDSR command are possible.
1	WEL	Write Enable Latch This indicates FeRAM Array and status register are writable. The WREN command is for setting, and the WRDI command is for resetting. With the RDSR command, reading is possible but writing is not possible with the WRSR command. WEL is reset after the following operations.  After power ON.  After WRDI command recognition.  After return from DPD mode.  After return from Hibernate mode.  Achieving continuous writing mode, WEL is not reset after following operations making it possible to execute writing commands continuously.  After WRSR command recognition.  After WRSN command recognition.  After SSWR command recognition.
0	0	This is a bit fixed to "0".

#### ■ OP-CODE

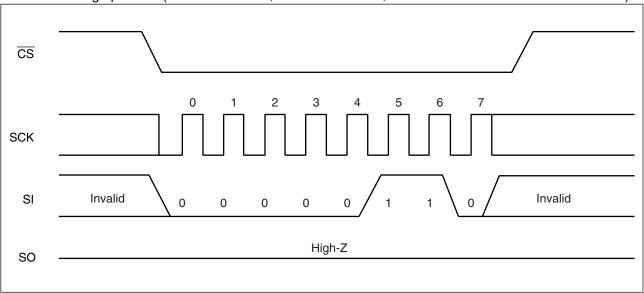
MB85RS256TYA accepts 16 kinds of command specified in op-code. Op-code is  $\overline{a}$  code composed of 8 bits shown in the table below. Do not input invalid codes other than those codes. If  $\overline{CS}$  is risen while inputting op-code, the command are not performed.

Name	Description	Op-code
WREN	Set Write Enable Latch	0000 0110в
WRDI	Reset Write Enable Latch	0000 0100в
RDSR	Read Status Register	0000 0101в
WRSR	Write Status Register	0000 0001в
READ	Read Memory Code	0000 0011в
WRITE	Write Memory Code	0000 0010в
FSTRD	Fast Read Memory Code	0000 1011в
DPD	Deep Power Down Mode	1011 1010в
HIBERNATE	Hibernate Mode	1011 1001в
RDID	Read Device ID	1001 1111в
RUID	Read Unique ID	0100 1100в
WRSN	Write Serial Number	1100 0010в
RDSN	Read Serial Number	1100 0011в
SSWR	Write Special Sector	0100 0010в
SSRD	Read Special Sector	0100 1011в
FSSRD	Fast Read Special Sector	0100 1001в
		1100 1110в
RFU	Reserved	1100 1111в
		1100 1100в

#### **■ COMMAND**

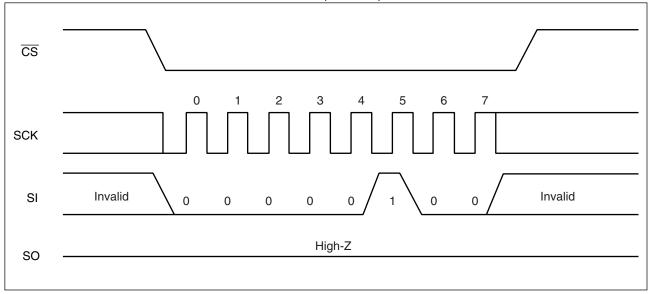
#### • WREN

The WREN command sets WEL (Write Enable Latch) bit to 1. WEL has to be set with the WREN command before writing operation (WRSR command, WRITE command, WRSN command and SSWR command).



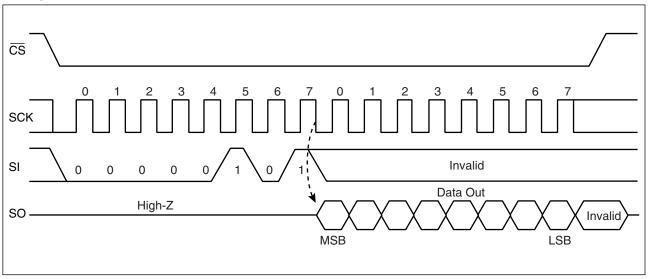
#### • WRDI

The WRDI command resets WEL (Write Enable Latch) bit to 0. Writing operation (WRSR command, WRITE command, WRSN command and SSWR command) are not performed when WEL is reset.



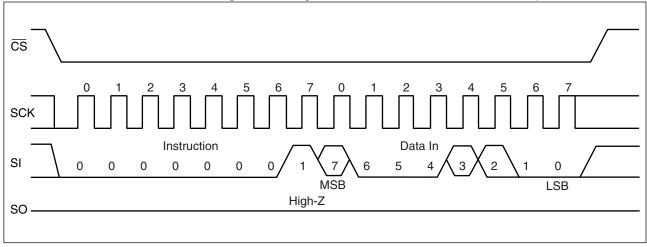
#### • RDSR

The RDSR command reads status register data. After op-code of RDSR is input to SI, 8-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. In the RDSR command, repeated reading of status register is enabled by sending SCK continuously before rising of  $\overline{\text{CS}}$ .



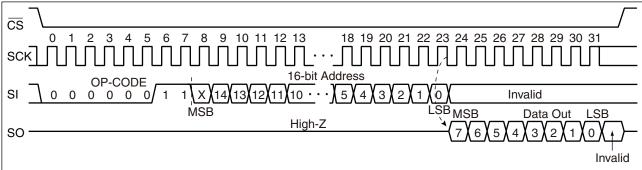
#### • WRSR

The WRSR command writes data to the nonvolatile memory bit of status register. After performing WRSR op-code to a SI pin, 8 bits writing data is input. WEL (Write Enable Latch) is not able to be written with WRSR command. A SI value correspondent to bit 1 is ignored. Bit <u>0</u> of the status register is fixed to "0" and cannot be written. The SI value corresponding to bit <u>0</u> is ignored. WP signal level shall be fixed before performing WRSR command, and do not change the WP signal level until the end of command sequence.



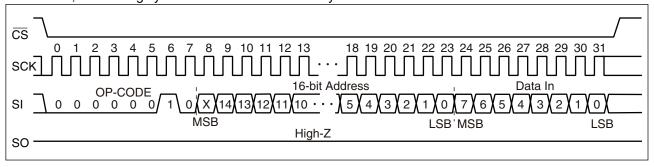
#### • READ

The READ command reads FeRAM memory cell array data. Arbitrary 16 bits address and op-code of READ are input to SI. The most significant address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When  $\overline{\text{CS}}$  is risen, the READ command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before  $\overline{\text{CS}}$  rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely.



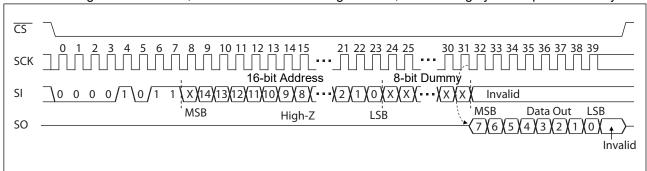
#### WRITE

The WRITE command writes data to FeRAM memory cell array. WRITE op-code, arbitrary 16 bits of address and 8 bits of writing data are input to SI. The most significant address bit is invalid. When 8 bits of writing data is input, data is written to FeRAM memory cell array. Risen  $\overline{CS}$  will terminate the WRITE command, but if you continue sending the writing data for 8 bits each before  $\overline{CS}$  rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, it rolls over to the starting address, and writing cycle can be continued infinitely.



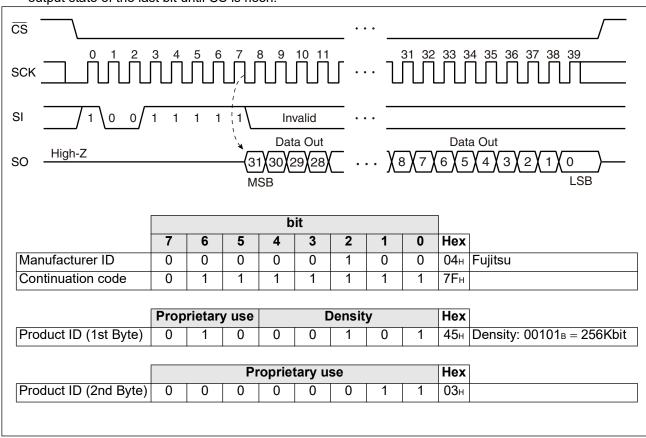
#### • FSTRD

The FSTRD command reads FeRAM memory cell array data. Arbitrary 16bits address and op-code of FSTRD are input to SI followed by 8 bits dummy. The 1-bit upper address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When CS is risen, the FSTRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before CS rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely.



#### • RDID

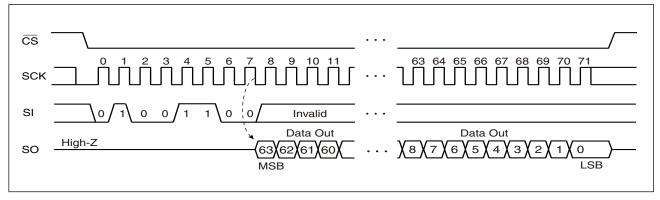
The RDID command reads fixed Device ID. After performing RDID op-code to SI, 32-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. The output is in order of Manufacturer ID (8bit)/Continuation code (8bit)/Product ID (1st Byte)/Product ID (2nd Byte). In the RDID command, 32-bit  $\overline{\text{Dev}}$  ice ID is output by continuously sending SCK clock, and SO holds the output state of the last bit until  $\overline{\text{CS}}$  is risen.



#### • RUID

The RUID command reads an unique ID which is defined in 64bits for each device. After performing RUID op-code to SI, 64-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK.

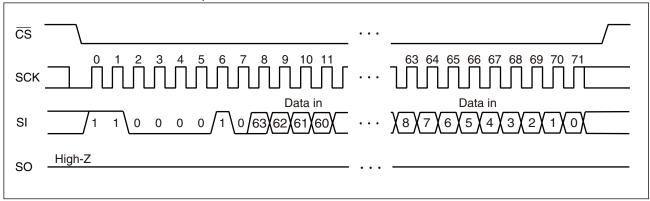
The unique ID is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



#### •WRSN

The WRSN command writes data to serial number region which is allowed to write only one time. After performing WRSN op-code to SI, 64bits of writing data is input. Once wrote, the serial number region is protected, disabling to overwrite even when issuing WRSN command.

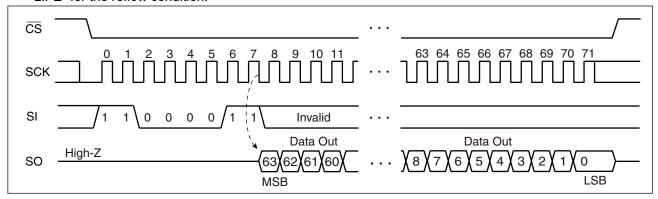
WP signal level shall be fixed before performing WRSN command, and do not change the WP signal level until the end of command sequence.



#### •RDSN

The RDSN command reads 64 bits of serial number which is written using WRSN command. After performing RDSN op-code to SI, 64-cycle clock to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. When reading serial number from devices which no WRSN command is executed, "0" for all bits are output.

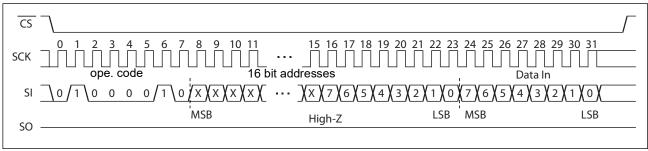
The serial number is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



#### • SSWR

The SSWR command writes data to special sector (a special region of 256 Byte in FeRAM). SSWR op-code, arbitrary 16 bits address and 8-bit writing data are input to SI. The 8-bit upper address is invalid. When input of 8-bit writing data is completed, it starts writing data to special sector. Risen  $\overline{\text{CS}}$  will terminate the SSWR command, but if you continue the writing data for each before  $\overline{\text{CS}}$  rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, roll over is not happen, the data hereafter is ignored.

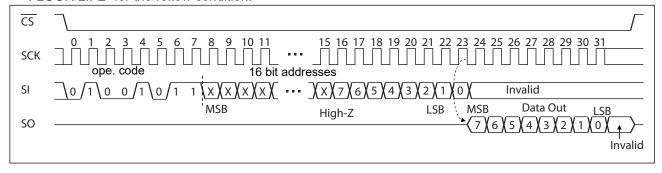
The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



#### • SSRD

The SSRD command reads data from special sector (a special region of 256 Byte in FeRAM). SSWR opcode and arbitrary 16 bits address are input to SI. The 8-bit upper address is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When  $\overline{\text{CS}}$  is risen, the SSRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before  $\overline{\text{CS}}$  rising. When it reaches the most significant address, roll over is not happen.

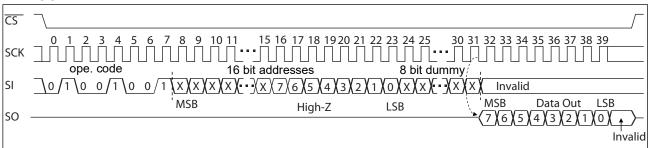
The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



#### • FSSRD

The SSRD command reads data from special sector (a special region of 256 Byte in FeRAM). SSWR opcode and arbitrary 16 bits address are input to SI followed by 8 bits dummy. The 8-bit upper address is invalid. Then, 8-cycle clock is input to  $\underline{SCK}$ . SO is output synchronously to the falling edge of  $\underline{SCK}$ . While reading, the SI value is invalid. When  $\underline{CS}$  is risen, the SSRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to  $\underline{SCK}$  in unit of 8 cycles before  $\underline{CS}$  rising. When it reaches the most significant address, roll over is not happen.

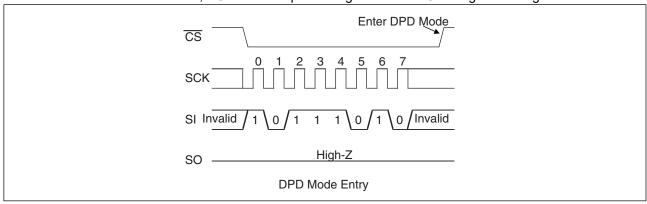
The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



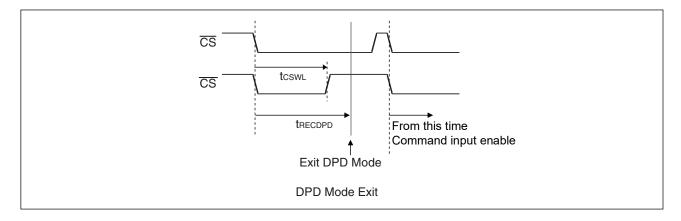
#### • DPD(Deep Power Down)

The DPD command shifts the LSI to a low power mode called "DPD mode". The transition to the DPD mode is carried out at the rising edge of  $\overline{CS}$  after operation code in the DPD command. However, when at least one SCK clock is inputted before the rising edge of  $\overline{CS}$  after operation code in the DPD command, this DPD command is canceled.

After the DPD mode transition, SCK and SI inputs are ignored and SO changes to a High-Z state.



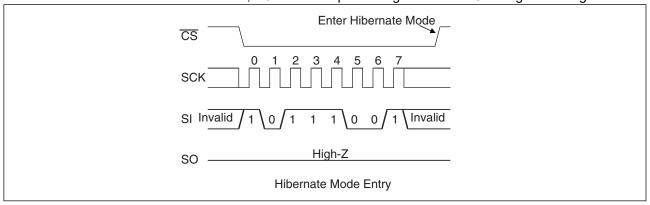
Returning to an normal operation from the DPD mode is carried out after  $t_{RECDPD}$  (Max 10  $\mu$ s) time from the falling edge of  $\overline{CS}$  (see the figure below). It is possible to return  $\overline{CS}$  to H level before  $t_{RECDPD}$  time. However, it is prohibited to bring down  $\overline{CS}$  to L level again during  $t_{RECDPD}$  period.



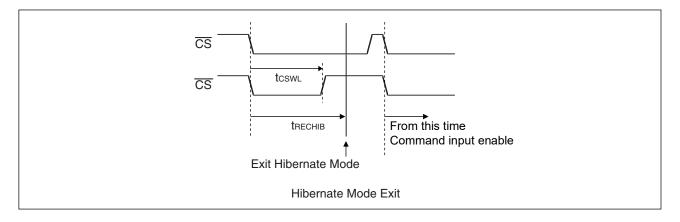
#### • HIBERNATE

The HIBERNATE command shifts the LSI to a low power mode called "HIBERNATE mode". The transition to the HIBERNATE mode is carried out at the rising edge of  $\overline{CS}$  after operation code in the HIBERNATE command. However, when at least one SCK clock is inputted before the rising edge of  $\overline{CS}$  after operation code in the HIBERNATE command, this HIBERNATE command is canceled.

After the HIBERNATE mode transition, SCK and SI inputs are ignored and SO changes to a High-Z state.



Returning to an normal operation from the HIBERNATE mode is carried out after  $t_{RECHIB}$  (Max 450  $\mu s$ ) time from the falling edge of  $\overline{CS}$  (see the figure below). It is possible to return  $\overline{CS}$  to H level before  $t_{RECHIB}$  time. However, it is prohibited to bring down  $\overline{CS}$  to L level again during  $t_{RECHIB}$  period.



#### **■ BLOCK PROTECT**

Writing protect block for WRITE command is configured by the value of BP0 and BP1 in the status register.

BP1	BP0	Protected Block
0	0	None
0	1	6000н to 7FFFн (upper 1/4)
1	0	4000н to 7FFFн (upper 1/2)
1	1	0000н to 7FFFн (all)

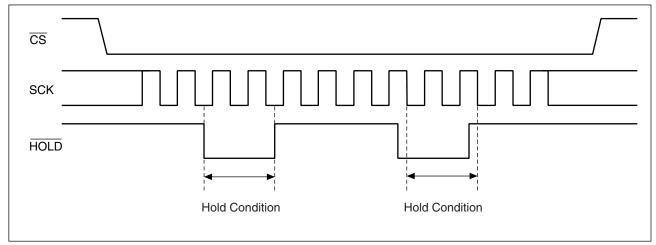
#### **■ WRITING PROTECT**

Writing operation of the WRITE command and the WRSR command are protected with the value of WEL, WPEN, WP as shown in the table.

WEL	WPEN	WP	Protected Blocks	Unprotected Blocks	Status Register
0	Х	Х	Protected	Protected	Protected
1	0	Х	Protected	Unprotected	Unprotected
1	1	0	Protected	Unprotected	Protected
1	1	1	Protected	Unprotected	Unprotected

#### **■ HOLD OPERATION**

Hold status is retained without aborting a command if HOLD is "L" level while  $\overline{CS}$  is "L" level. The timing for starting and ending hold status depends on the SCK to be "H" level or "L" level when a HOLD pin input is transited to the hold condition as shown in the diagram below. In case the HOLD pin transited to "L" level when SCK is "L" level, return the HOLD pin to "H" level at SCK being "L" level. In the same manner, in case the HOLD pin transited to "L" level when SCK is "H" level, return the HOLD pin to "H" level at SCK being "H" level. Arbitrary command operation is interrupted in hold status, SCK and SI inputs become do not care. And, SO becomes High-Z while reading command (RDSR, READ). If  $\overline{CS}$  is rising during hold status, a command is aborted. In case the command is aborted before its recognition, WEL holds the value before transition to hold status.



#### ■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rat	Unit	
Farameter	Symbol	Min	Max	Oilit
Power supply voltage*	$V_{DD}$	- 0.5	+ 4.0	V
Input voltage*	Vin	- 0.5	$V_{DD} + 0.5 (\le 4.0)$	V
Output voltage*	Vоит	- 0.5	$V_{DD} + 0.5 (\le 4.0)$	V
Operation ambient temperature	TA	<b>- 40</b>	+ 125	°C
Storage temperature	Tstg	<b>– 55</b>	+ 150	°C

<sup>\*:</sup> These parameters are based on the condition that Vss is 0 V.

WARNING: Semiconductor devices may be permanently damaged by application of stress (including, without limitation, voltage, current or temperature) in excess of absolute maximum ratings. Do not exceed any of these ratings.

#### ■ RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol		Unit		
Faranietei	Symbol	Min	Тур	Max	Offic
Power supply voltage*1	V <sub>DD</sub>	1.8	3.3	3.6	V
Operation ambient temperature*2	TA	- 40	_	+ 125	°C

<sup>\*1:</sup> These parameters are based on the condition that Vss is 0 V.

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated under these conditions.

Any use of semiconductor devices will be under their recommended operating condition. Operation under any conditions other than these conditions may adversely affect reliability of device and could result in device failure.

No warranty is made with respect to any use, operating conditions or combinations not represented on this data sheet. If you are considering application under any conditions other than listed herein, please contact sales representatives beforehand.

<sup>\*2:</sup> Ambient temperature when only this device is working. Please consider it to be the almost same as the package surface temperature.

#### **■ ELECTRICAL CHARACTERISTICS**

#### 1. DC Characteristics

(within recommended operating conditions)

					Value			
Parameter	Sym- bol	Condition		Min	<b>Typ</b> (T <sub>A</sub> =25 °C)	Max	Unit	
		$\overline{CS} = V_{DD}$	25 °C	_	_	1		
		CS = VDD	125 °C	_	_	2		
Input lookage ourrent*1	H. J	WP, SCK, CS	25 °C	_	_	1	^	
Input leakage current*1	lu	$SI = 0 V \text{ to } V_{DD}$	125 °C	_	_	2	μΑ	
		HOLD = 0 V to	25 °C	_	_	100		
		V <sub>DD</sub>	125 °C	_	_	100		
Output leakage current*2	ILO	SO = 0 V to V <sub>DD</sub>	25 °C	_	_	1	μА	
Output leakage current		30 = 0 0 10 000	125 °C	_	_	2		
Operating power supply current*3	ldd	SCK = 50N	SCK = 50MHz		3.10	3.7	mA	
Standby current	İsb	SCK = SI = 0 $\overline{WP} = V_{L}$		_	17.0	150	μА	
Hibernate current	І́гинв	CS = V <sub>D</sub> All inputs Vss		_	0.4	10	μА	
DPD current	IZZDPD	_	CS = V <sub>DD</sub> All inputs Vss or V <sub>DD</sub>		5.76	30	μА	
Input high voltage	VIH	V <sub>DD</sub> = 1.8 V to	V <sub>DD</sub> = 1.8 V to 3.6 V		_	V <sub>DD</sub> + 0.5	V	
Input low voltage	VIL	V <sub>DD</sub> = 1.8 V to 3.6 V		- 0.5	_	$V_{\text{DD}} \times 0.2$	V	
Output high voltage	Vон	lон = − 2 mA		V <sub>DD</sub> - 0.5	_		V	
Output low voltage	Vol	IoL = 2 mA		_	_	0.4	V	
Pull up resistance for HOLD	R₽	_		36	66	230	kΩ	

<sup>\*1 :</sup> Applicable pin :  $\overline{\text{CS}}$ ,  $\overline{\text{WP}}$ , SCK, SI

<sup>\*2 :</sup> Applicable pin : SO

<sup>\*3 :</sup> Input voltage magnitude : VDD - 0.2 V or VSS

#### 2. AC Characteristics

Davamatav	Currele el	Va	alue	Unit	Condition	
Parameter	Symbol	Min	Max	Unit	V <sub>DD</sub>	
SCK clock frequency	fск	_	- 50	MHz	all commands ex- cept for READ/ SSRD	
, ,		_	40		READ command	
		_	10		SSRD command	
Clock high time	tсн	9	_	ns		
Clock low time	<b>t</b> cL	9	_	ns		
Chip select set up time	<b>t</b> csu	5	_	ns		
Chip select hold time	tсsн	5		ns		
Output disable time	<b>t</b> op	_	10	ns		
Output data valid time	todv	_	9	ns	*1	
Output hold time	<b>t</b> он	0	_	ns		
Deselect time	<b>t</b> D	40	_	ns		
Data in rising time	<b>t</b> R	_	50	ns		
Data falling time	t⊧	_	50	ns		
Data set up time	<b>t</b> su	5		ns		
Data hold time	tн	5	_	ns		
HOLD set uptime	<b>t</b> Hs	10	_	ns	_	
HOLD hold time	tнн	10		ns	_	
HOLD output floating time	<b>t</b> HZ	_	20	ns	_	
HOLD output active time	<b>t</b> LZ	_	20	ns	_	
DPD/Hibernate recovery pulse width	<b>t</b> cswL	100	_	ns		
DPD recovery time	<b>t</b> RECDPD		10	μS		
Hibernate recovery time	<b>t</b> RECHIB		450	μS		

<sup>\*1:</sup> In SSRD command, 60ns(max.)

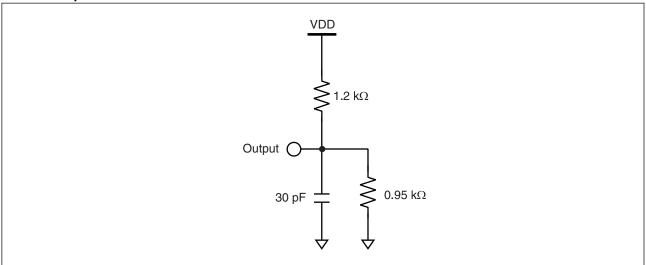
#### **AC Test Condition**

 $\begin{array}{lll} \mbox{Power supply voltage} & : 1.8 \ \mbox{V to } 3.6 \ \mbox{V} \ \mbox{Operation} \\ \mbox{Operation ambient temperature} & : -40 \ \mbox{°C to} \ + 125 \ \mbox{°C} \\ \mbox{Input voltage magnitude} & : \mbox{V}_{DD} \times 0.8 \le \mbox{V}_{IH} \le \mbox{V}_{DD} \\ \end{array}$ 

 $0 \leq V_{\text{IL}} \leq V_{\text{DD}} \times 0.2$ 

Input rising time : 5 ns Input falling time : 5 ns Input judge level : VDD/2 Output judge level : VDD/2

#### **AC Load Equivalent Circuit**

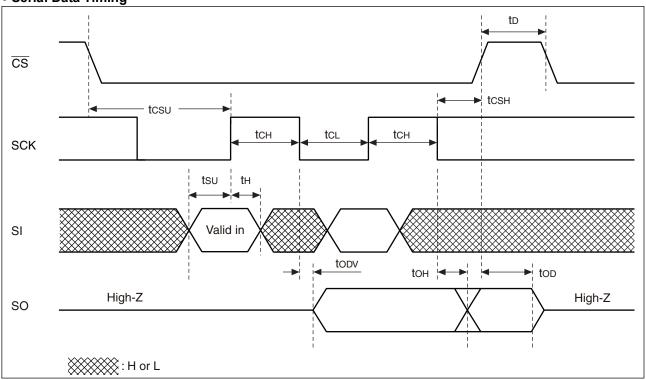


## 3. Pin Capacitance

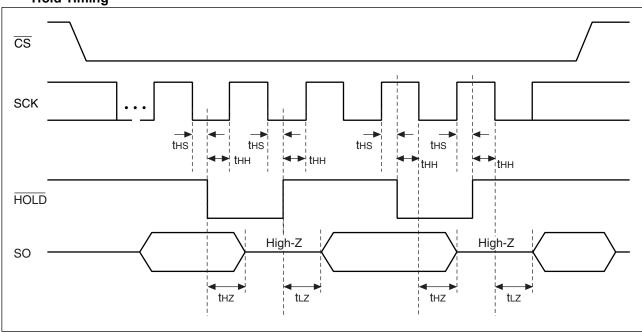
Parameter	Symbol	Condition	Va	Unit	
Farameter	Symbol	Condition	Min	Max	Oille
Output capacitance	Со	$V_{DD} = 3.3 \text{ V},$ $V_{IN} = V_{OUT} = 0 \text{ V to } V_{DD},$	_	8	pF
Input capacitance	Cı	f = 1 MHz, T <sub>A</sub> = +25 °C	_	6	pF

#### **■ TIMING DIAGRAM**

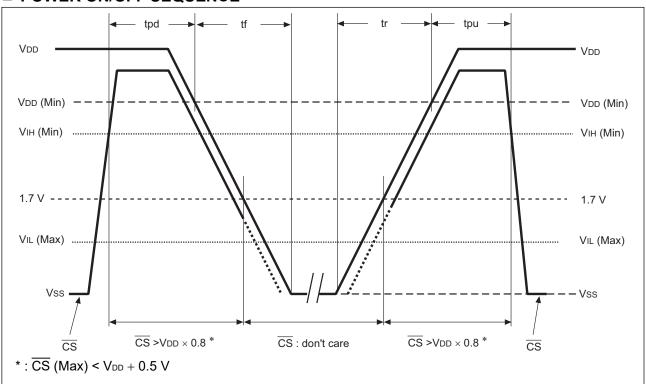
#### • Serial Data Timing



#### Hold Timing



#### **■ POWER ON/OFF SEQUENCE**



In case relative short  $V_{DD}$  pulse whose peak level is beyond 1.7 is applied, please set  $V_{DD}$  falling time, tf, longer than 0.4ms/V. (When  $V_{DD}$  rises beyond 1.7V, and falls just after, if this term is very short the device may loose its function.).

Downwater	Cumbal	Value		Linit	Condition
Parameter	Symbol	Min	Max	Unit	V <sub>DD</sub>
CS level hold time at power OFF	tnd	400	_	ne	1.8V to 2.7V
C3 level floid time at power OFF	tpd	0		ns	2.7V to 3.6V
CS level hold time at power ON	tpu	450	_	μS	_
Power supply rising time	tr	0.05		ms/V	_
Power supply falling time	tf	0.1		ms/V	_

If the device does not operate within the specified conditions of read cycle, write cycle or power on/off sequence, memory data can not be guaranteed.

#### **■ FeRAM CHARACTERISTICS**

Parameter	Value		Unit	Remarks	
Farameter	Min	Max	Oill	Remarks	
Read/Write Endurance*1	10 <sup>13</sup>	_	Times/byte	Operation Ambient Temperature T <sub>A</sub> = + 125 °C	
	5.9 or more*3			Operation Ambient Temperature T <sub>A</sub> = + 125 °C	
Data Retention*2	19.1	_	Years	Operation Ambient Temperature T <sub>A</sub> = + 105 °C	
	70.4			Operation Ambient Temperature T <sub>A</sub> = + 85 °C	

<sup>\*1 :</sup> Total number of reading and writing defines the minimum value of endurance, as an FeRAM memory operates with destructive readout mechanism.

#### ■ NOTE ON USE

We recommend programming of the device after reflow except for special sector region and serial number region. Data written before reflow cannot be guaranteed.

#### **■ ESD AND LATCH-UP**

Test	DUT	Value
ESD HBM (Human Body Model) JESD22-A114 compliant		≥  2000 V
ESD CDM (Charged Device Model) JESD22-C101	MB85RS256TYAPNF-G-BCE1 MB85RS256TYAPNF-G-BCERE1	≥  1000 V
Latch-Up (I-test) JESD78 compliant	MB85RS256TYAPN-G-AWE1 MB85RS256TYAPN-G-AWEWE1	≥  125mA
Latch-Up (V <sub>supply</sub> overvoltage test) JESD78 compliant		≥ 5.4V

#### ■ REFLOW CONDITIONS AND FLOOR LIFE

[ JEDEC MSL ] : Moisture Sensitivity Level 3 (IPC/JEDEC J-STD-020E)

#### ■ Current status on Contained Restricted Substances

This product complies with the regulations of REACH Regulations, EU RoHS Directive and China RoHS.

<sup>\*2:</sup> Minimum values define retention time of the first reading/writing data right after shipment, and these values are calculated by qualification results.

<sup>\*3:</sup> Under evaluation for more than 5.9 years(+125 °C).

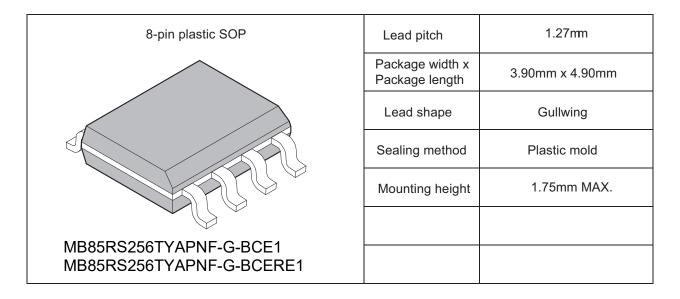
## ■ ORDERING INFORMATION:

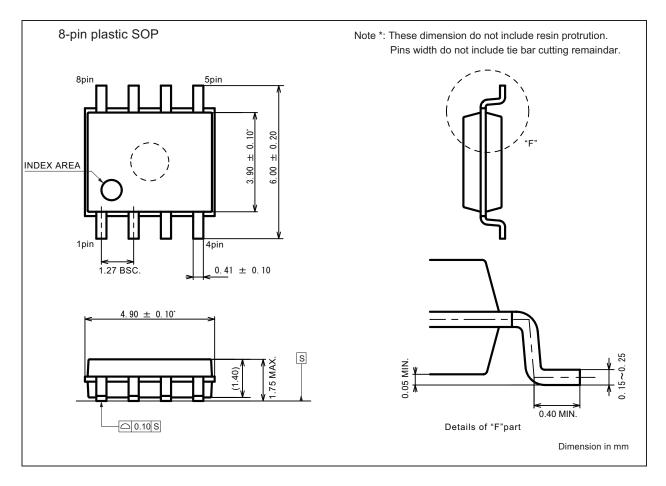
Part number	Package	Shipping form	Minimum shipping quantity
MB85RS256TYAPNF-G-BCE1	8-pin plastic SOP	Tube	*
MB85RS256TYAPNF-G-BCERE1	8-pin plastic SOP	Embossed Carrier tape	1500
MB85RS256TYAPN-G-AWE1	8-pin plastic DFN	Tray	*
MB85RS256TYAPN-G-AWEWE1	8-pin plastic DFN	Embossed Carrier tape	1500

<sup>\* :</sup> Please contact our sales office about minimum shipping quantity.

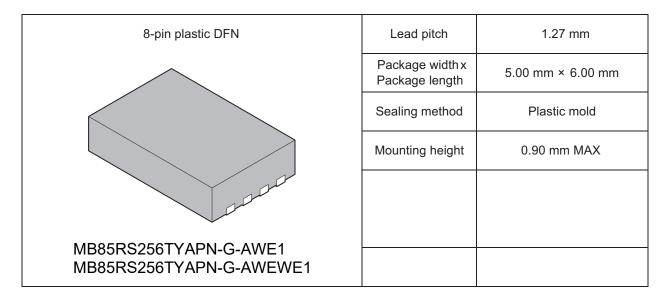
#### **■ PACKAGE DIMENSION**

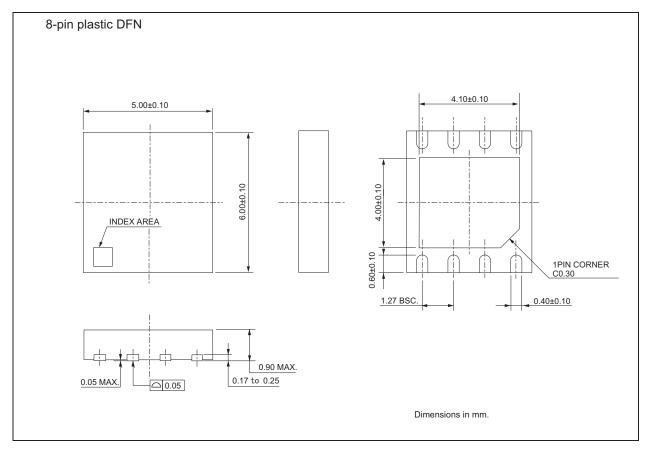
#### (1) MB85RS256TYAPNF-G-BCE1/MB85RS256TYAPNF-G-BCERE1





#### (2) MB85RS256TYAPN-G-AWE1/MB85RS256TYAPN-G-AWEWE1





#### ■ MARKING (Example)

(1) MB85RS256TYAPNF-G-BCE1/MB85RS256TYAPNF-G-BCERE1

[MB85RS256TYAPNF-G-BCE1] [MB85RS256TYAPNF-G-BCERE1]

# S2TYA 12300 V01

S2TYA: Product name

12300 : 1(CS code) + 2300(Year and Week code)

V01: Trace code

#### (2) MB85RS256TYAPN-G-AWE1/MB85RS256TYAPN-G-AWEWE1

[MB85RS256TYAPN-G-AWE1] [MB85RS256TYAPN-G-AWEWE1]



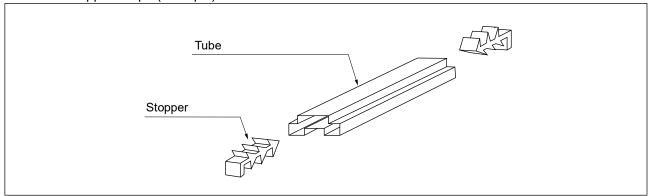
85RS256TYA: Product name

1E1 : 1(CS code) + E1(Environmental code)

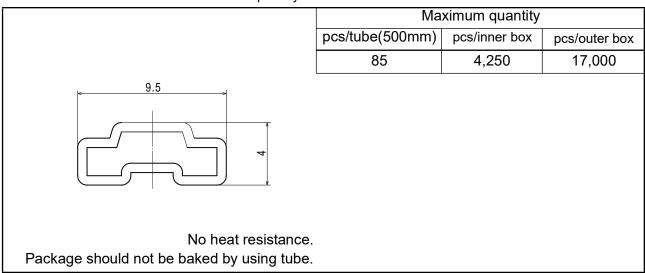
2300R00: 2300(Year and Week code) + R00(Trace code)

#### **■ PACKING INFORMATION**

- (1) MB85RS256TYAPNF-G-BCE1/MB85RS256TYAPNF-G-BCERE1
- **1. Tube** (MB85RS256TYAPNF-G-BCE1)
- 1.1 Tube Dimensions
  - Tube/stopper shape (example)

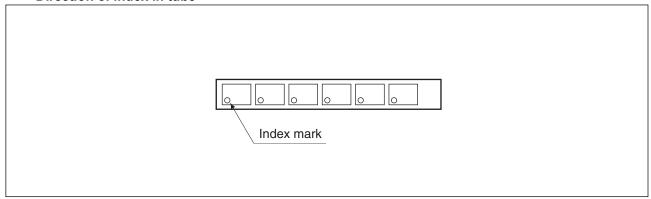


• Tube cross-sections and Maximum quantity



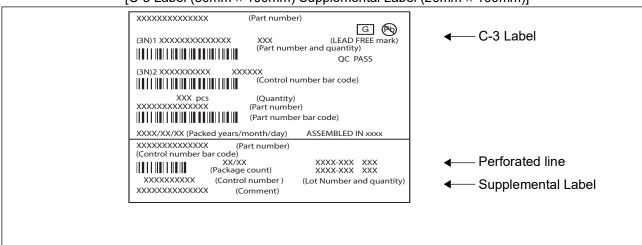
(Dimensions in mm)

· Direction of index in tube



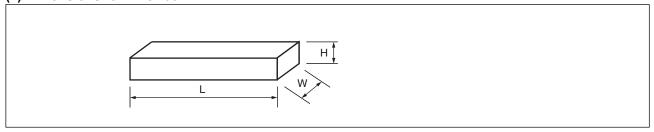
#### 1.2 Product label indicators (example)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label ( $50 \text{mm} \times 100 \text{mm}$ ) Supplemental Label ( $20 \text{mm} \times 100 \text{mm}$ )]



#### 1.3 Dimensions for Containers

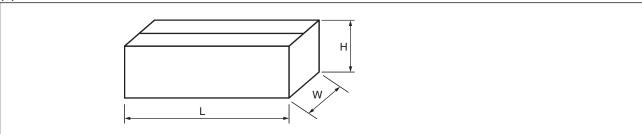
#### (1) Dimensions for inner box



L	W	Н
540	125	75

(Dimensions in mm)

#### (2) Dimensions for outer box



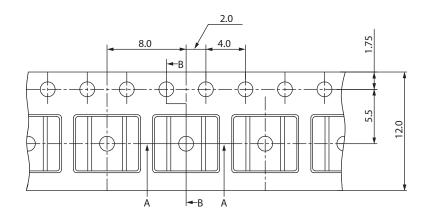
L	W	Н
565	270	180

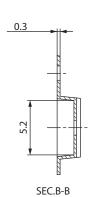
(Dimensions in mm)

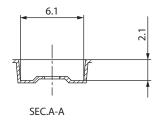
## 2. Emboss Tape (MB85RS256TYAPNF-G-BCERE1)

## 2.1 Tape Dimensions (not drawn to scale) (8-pin plastic SOP)

Maximum storage capacity		
pcs/reel(Ф254mm) pcs/inner box pcs/uter boxo		
1500	1500 (1 pack/inner box)	9000 (6 inner boxes/outer box:Max)







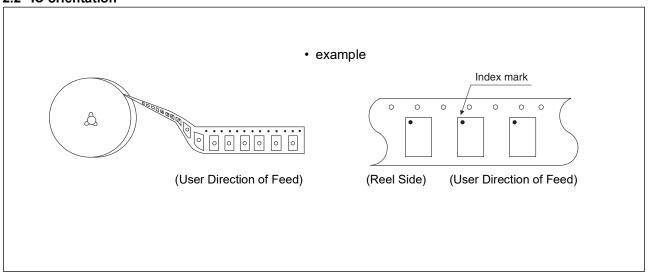
(Dimensions in mm)

Heat proof temperature : No heat resistance.

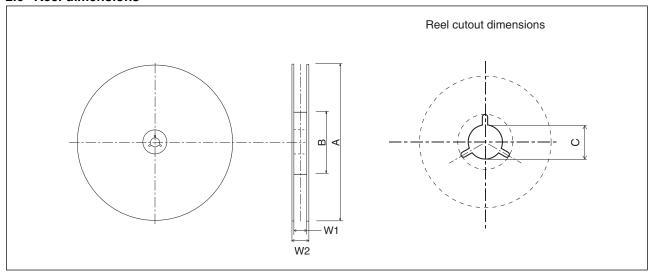
Package should not be baked by

using tape and reel.

#### 2.2 IC orientation



#### 2.3 Reel dimensions

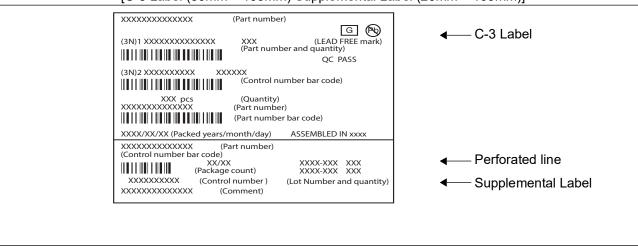


Dimensions in mm

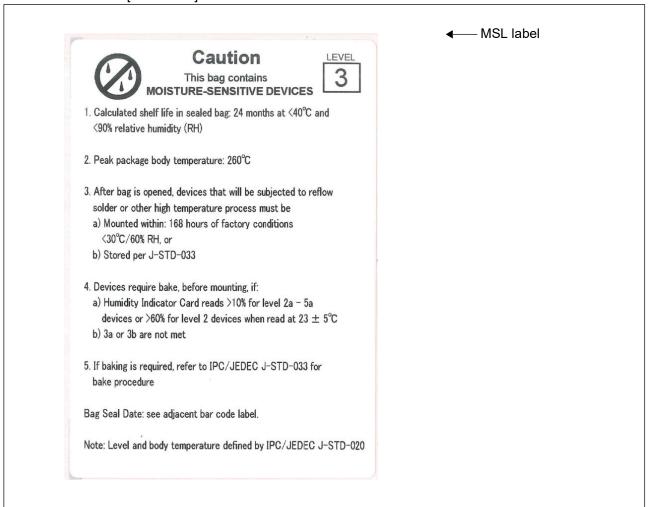
Α	В	С	W1	W2
254	100	13	13.5	17.5

#### 2.4 Product label indicators (examples)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]

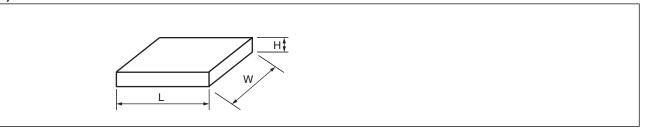


Label II:Moisture Barrier Bag (It sticks it on the Aluminum laminated bag)
[MSL Label]



#### 2.5 Dimensions for Containers

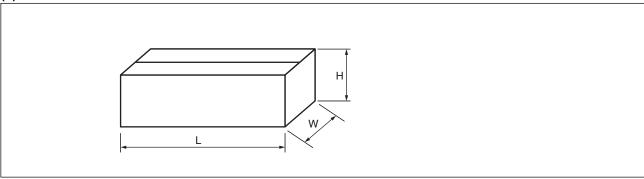
#### (1) Dimensions for inner box



Tape width	L	W	Н
12	266	263	52

(Dimensions in mm)

#### (2) Dimensions for outer box



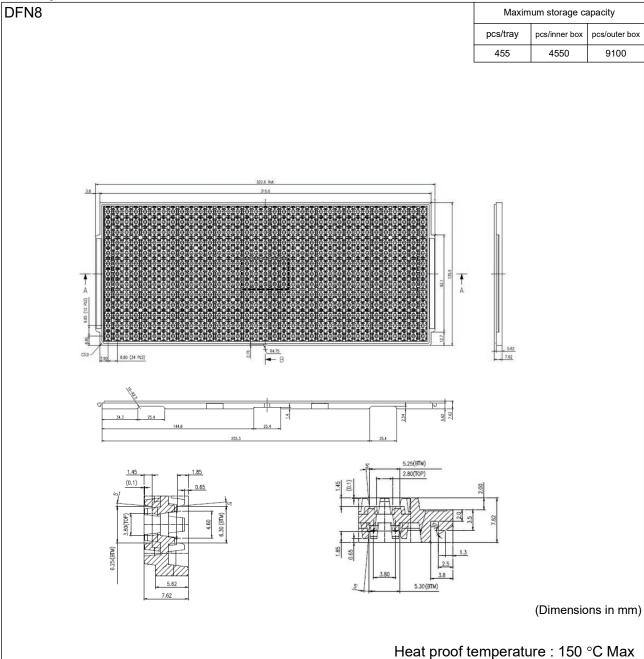
L	W	Н
555	255	160

(Dimensions in mm)

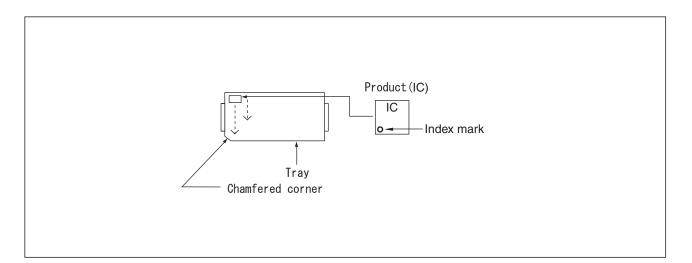
## (2) MB85RS256TYAPN-G-AWE1/MB85RS256TYAPN-G-AWEWE1

1. Tray (MB85RS256TYAPN-G-AWE1)

#### 1.1 Tray Dimensions

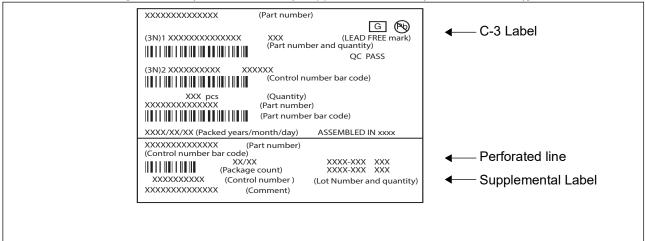


#### 1.2 IC orientation



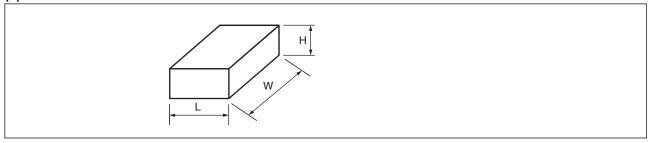
#### 1.3 Product label indicators(example)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]



#### 1.4 Dimensions for Containers

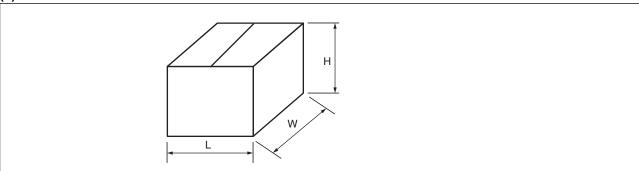
#### (1) Dimensions for inner box



L	W	Н
175	375	110

(Dimensions in mm)

#### (2) Dimensions for outer box



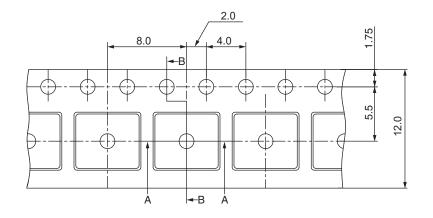
L	W	Н
190	380	330

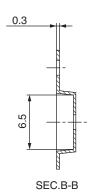
(Dimensions in mm)

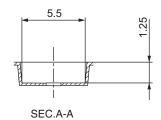
## 2. Emboss Tape (MB85RS256TYAPN-G-AWEWE1)

#### **2.1 Tape Dimensions** (not drawn to scale)(8-pin plastic DFN 5mm × 6mm)

Maximum storage capacity			
pcs/reel(Φ330mm) pcs/inner box pcs/uter boxo			
1500	1500 (1 pack/inner box)	7500 (5 inner boxes/outer box:Max)	







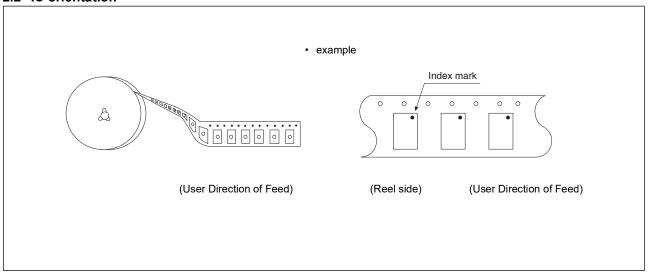
(Dimensions in mm)

Heat proof temperature : No heat resistance.

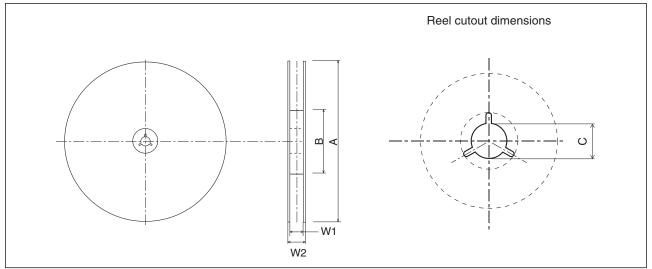
Package should not be baked by using tape and

reel.

#### 2.2 IC orientation



#### 2.3 Reel dimensions

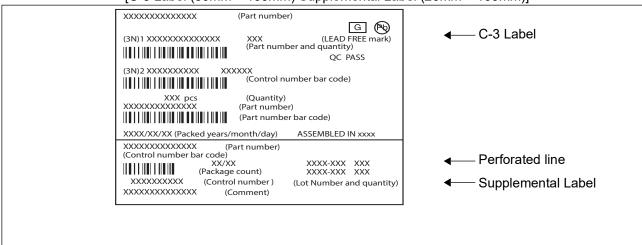


Dimensions in mm

А	В	С	W1	W2
330	100	13	13.5	17.5

#### 2.4 Product label indicators (example)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]



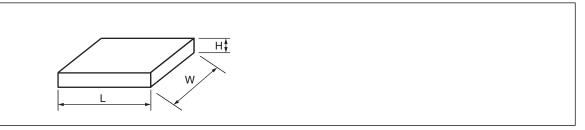
Label II: Moisture Barrier Bag (It sticks it on the Aluminum laminated bag)

[MSL Label]



#### 2.5 Dimensions for Containers

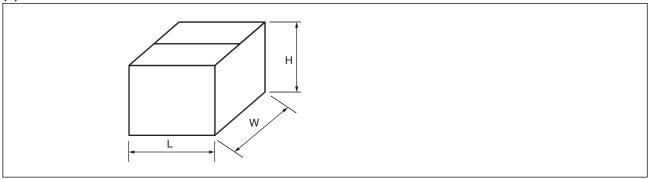
#### (1) Dimensions for inner box



Tape width	L	W	Н
12	350	335	35

(Dimensions in mm)

#### (2) Dimensions for outer box



L	W	Н
384	368	225

(Dimensions in mm)

#### RAMXEED LIMITED

Shin-Yokohama Chuo Building, 2-100-45 Shin-Yokohama, Kohoku-ku, Yokohama, Kanagawa 222-0033, Japan https://ramxeed.com/

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